

## 20V, 13A DUAL N-CHANNEL POWER MOSFET

### GENERAL DESCRIPTION

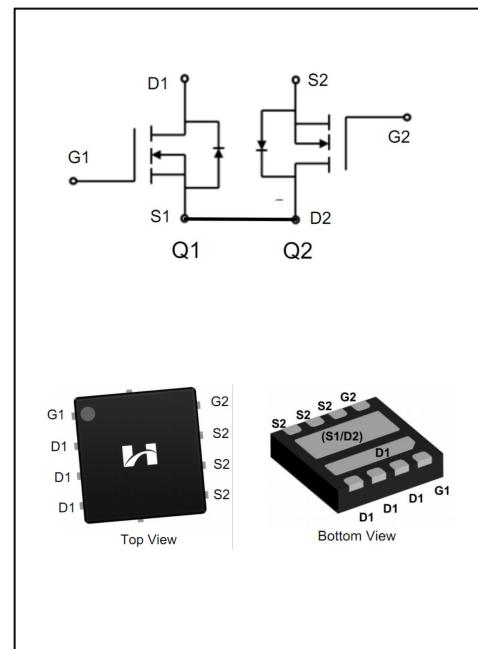
The SFN0213T2 uses advanced trench technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

### Features

- ◆  $V_{DS}=20V, I_D=13A$
- ◆  $R_{DS(on)}$
- ◆ TYP:  $6.0m\Omega @ V_{GS}=4.5V$

### Applications

- ◆ Power factor correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SFN0213T2	DFN3*3-8L	SFN0213T2	Pb Free	Reel

**ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)**

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	20	V
Gate-Source Voltage	V <sub>GS</sub>	±12	V
Drain Current	I <sub>D</sub>	13	A
T <sub>C</sub> = 100°C	I <sub>D</sub>	9.1	
Drain Current Pulsed(Note 1)	I <sub>DM</sub>	52	A
Power Dissipation(T <sub>C</sub> =25°C)	P <sub>D</sub>	1.86	W
Operation Junction Temperature Range	T <sub>J</sub>	-55~+150	°C
Storage Temperature Range	T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	TL	300	°C

**THERMAL CHARACTERISTICS**

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	67	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	80	°C/W

**ELECTRICAL CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
Drain -Source Breakdown Voltage	B <sub>VDSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20	--	--	V
Drain-Source Leakage Current	I <sub>DS</sub>	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V	--	--	1.0	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =12V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-12V, V <sub>DS</sub> =0V	--	--	-100	
<b>On Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	0.5	0.65	0.9	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A	--	6.0	7.0	mΩ
		V <sub>GS</sub> =3.8V, I <sub>D</sub> =5A	--	6.3	8.0	
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =5A	--	7.1	9.0	
<b>Dynamic Characteristics</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V V <sub>GS</sub> =0V f=1.0MHZ	--	1767	--	pF
Output Capacitance	C <sub>oss</sub>		--	164	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	155	--	
<b>Switching Characteristics</b>						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =16V, R <sub>G</sub> =6Ω I <sub>D</sub> =6.5A (Note 2.3)	--	11.2	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	42	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	68	--	
Turn-off Fall Time	t <sub>f</sub>		--	32	--	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =16V, I <sub>D</sub> =13A V <sub>GS</sub> =4.5V (Note 2.3)	--	24	--	nc
Gate-Source Charge	Q <sub>gs</sub>		--	3.7	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	8.6	--	

**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	13	A
Pulsed Source Current	$I_{SM}$		--	--	52	
Diode Forward Voltage	$V_{SD}$	$I_S=6A, V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	$T_{rr}$	$I_F=13A$ $dI/dt=100A/\mu s$	--	48	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	10.9	--	$\mu C$

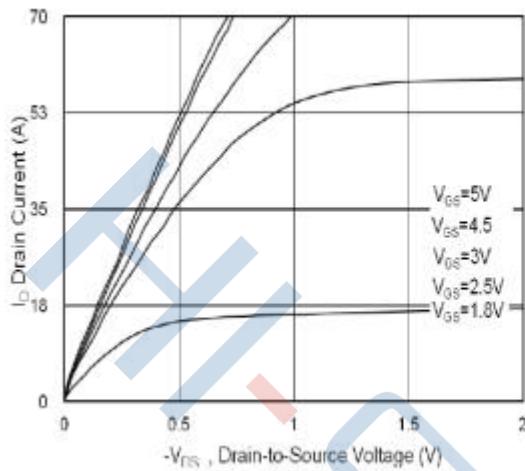
1. Pulse width limited by maximum junction temperature

2. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$

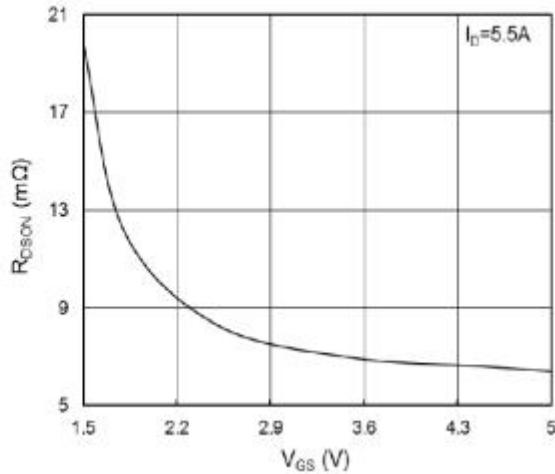
3. Essentially independent of operating temperature

## Typical Performance Characteristics

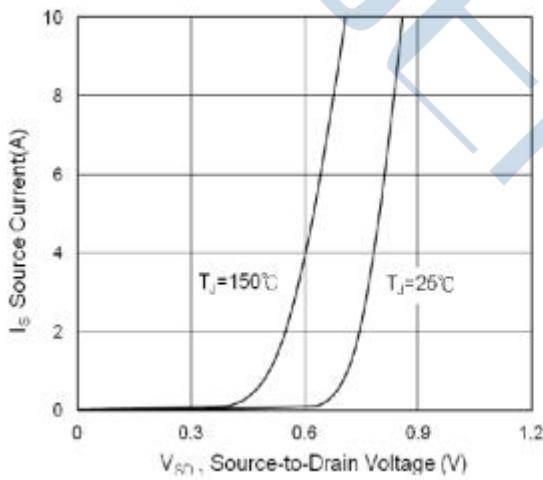
**Fig.1 Typical Output Characteristics**



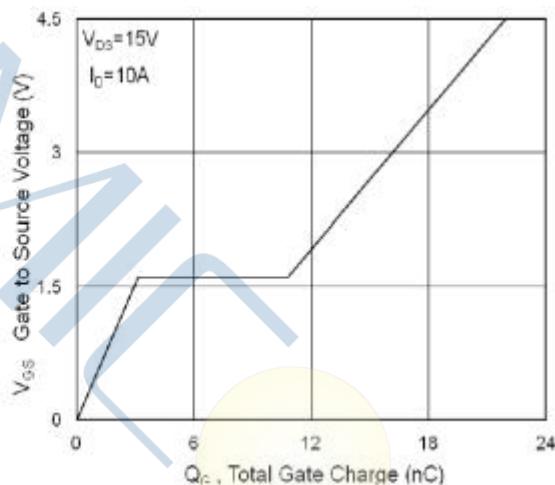
**Fig.2 On-Resistance vs.Gate-Source**



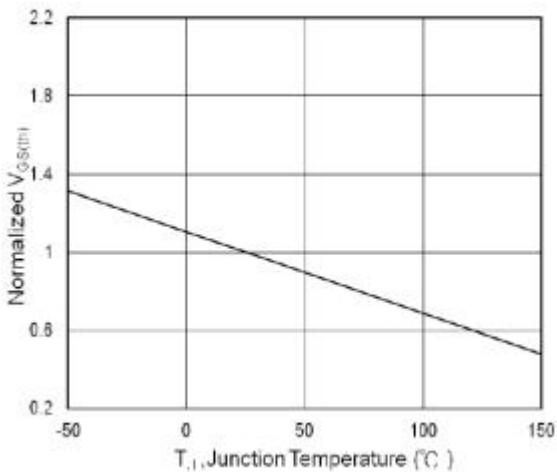
**Fig.3 Forward Characteristics of Reverse**



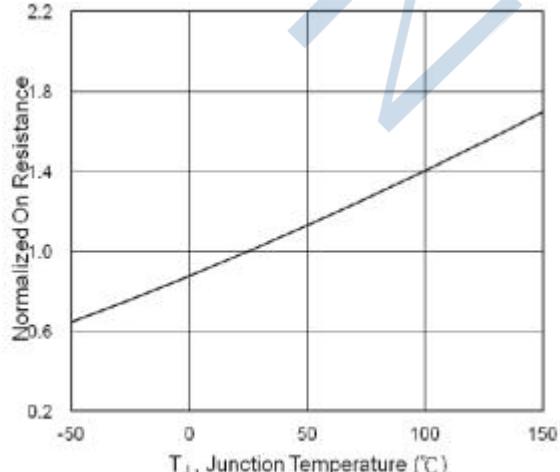
**Fig.4 Gate-Charge Characteristics**



**Fig.5  $V_{GS(th)}$ vs. $T_J$**



**Fig.6 Normalized  $R_{DS(on)}$  vs. $T_J$**



## Typical Performance Characteristics

Fig.7 Capacitance

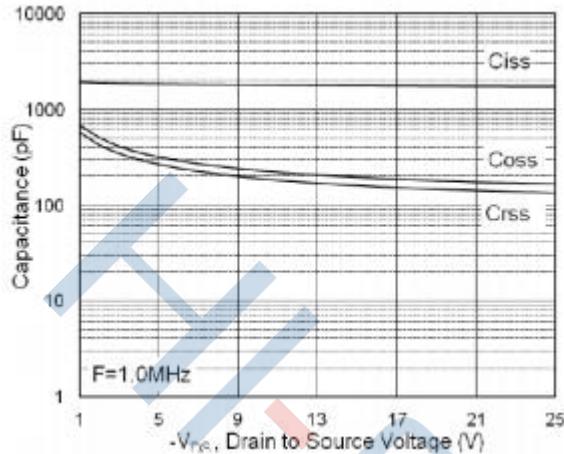
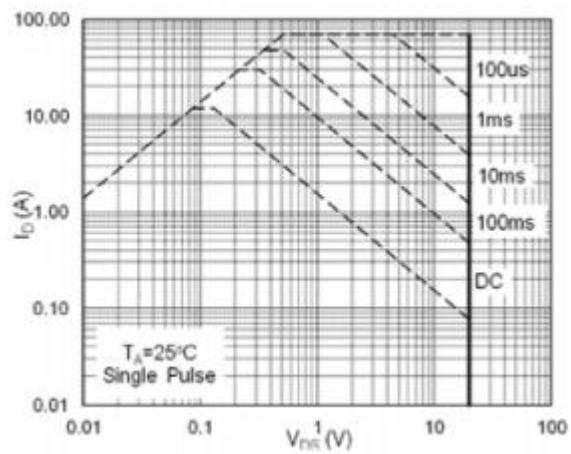
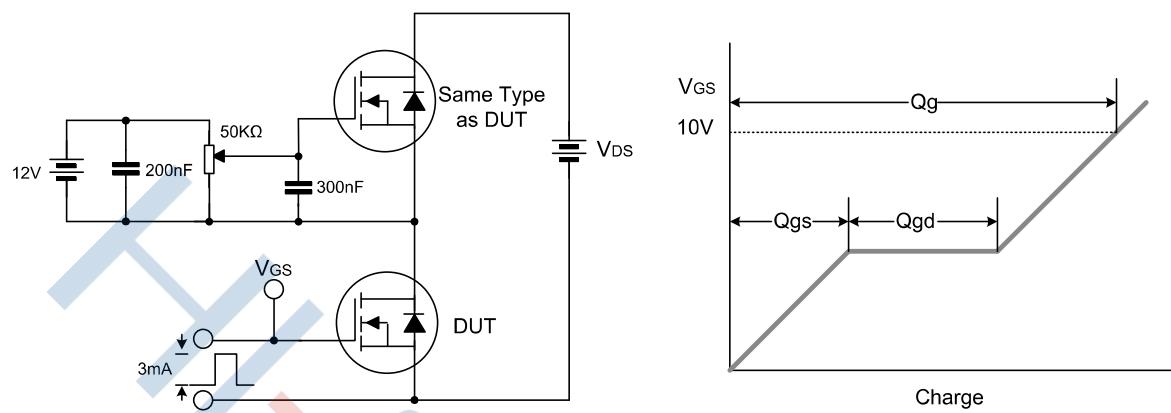


Fig.8 Safe Operating Area

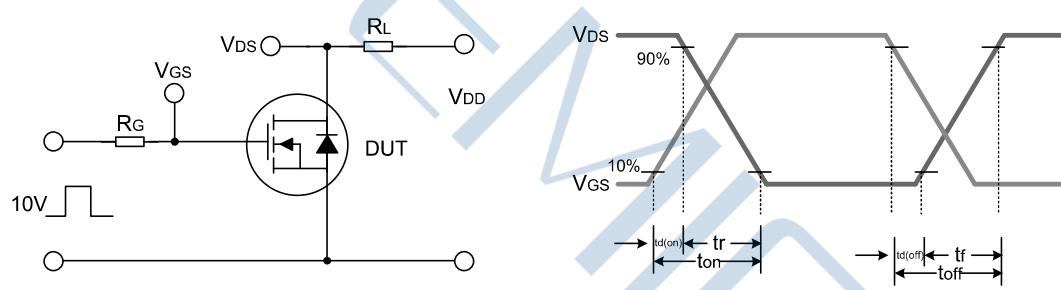


## Test Circuit

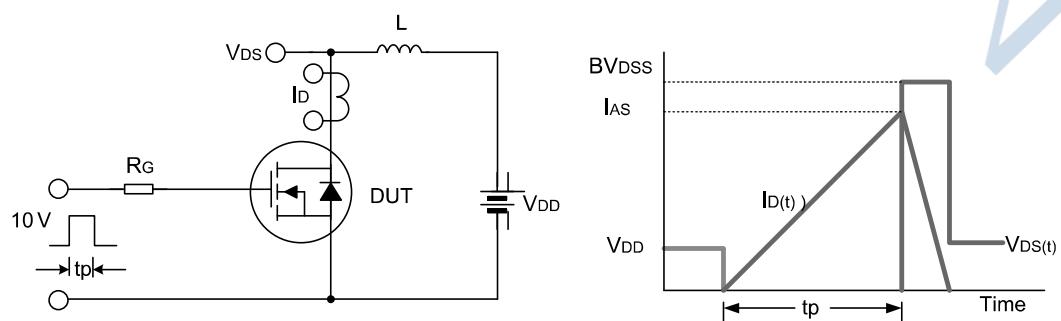
Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveform

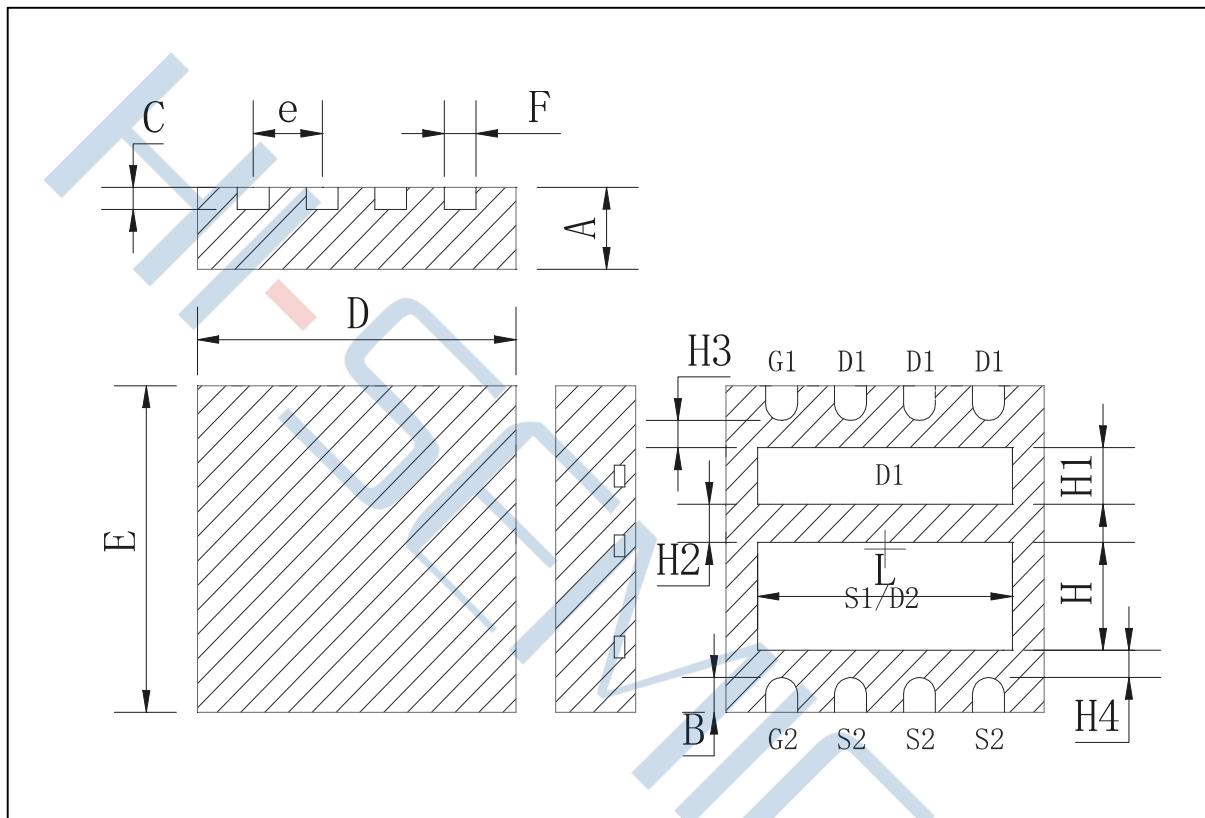


Undamped Inductive Switching Test Circuit &amp; Waveform



## Package Dimensions of DFN3\*3-8L

Unit:mm



Symbol	Min	Typ	Max
A	0.70	0.75	0.80
B	0.27	0.32	0.37
C	0.153	0.203	0.253
D	2.90	3.00	3.10
E	2.90	3.00	3.10
e	0.60	0.65	0.70
F	0.25	0.30	0.35
H	0.89	0.99	1.09
H1	0.42	0.52	0.62
H2	0.25	0.35	0.45
H3	0.15	0.25	0.35
H4	0.15	0.25	0.35
L	2.30	2.40	2.50

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